

Product Change Notification / ALAN-24AINW535

Date:

17-Nov-2022

Product Category:

Memory

PCN Type:

Manufacturing Change

Notification Subject:

CCB 5336 Final Notice: Qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers (CPN) available in 8L SOIJ (.208in) package.

Affected CPNs:

ALAN-24AINW535_Affected_CPN_11172022.pdf ALAN-24AINW535_Affected_CPN_11172022.csv

Notification Text:

PCN Status: Final Notification

PCN Type:Manufacturing Change

Microchip Parts Affected:Please open one of the files found in the Affected CPNs section. Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change:Qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers (CPN) available in 8L SOIJ (.208in) package.

Pre and Post Change Summary:

| Pre Change | Post Change |
|------------|-------------|
| | |

| Assembly Site | Greatek Electronic Inc. (GTK) | Lingsen Precision Industries, LTD. (LPI) | Microchip Technology Thailand (MTAI) |
|------------------------------|----------------------------------|--|--|
| Wire Material | Au | Au | Au |
| Die Attach Material | 8340 | 8340 | 8390A |
| Molding Compound Material | G600 | G600 | G600V |
| Lead-Frame Material | C194 | C194 | CDA194 |
| Lead-Frame Paddle Size | 140 x 160 mils | 142 x 168 mils | 140 x 160 mils |
| DAP Surface Prep | face Prep Ag spot | | Bare Cu |
| MSL | 3 | 3 | 1 |
| See Pre and | Post Change Summary | / attachment for con | nparison |

Impacts to Data Sheet:None

Change ImpactNone

Reason for Change:To improve manufacturability and on-time delivery performance by qualifying MTAI as a new assembly site.

Change Implementation Status: In Progress

Estimated First Ship Date:November 25, 2022 (date code: 2248)

Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Due to unforeseen circumstances, that are out of Microchip's control, full qualification will be made available as soon as it is approved which may be after the estimated first ship date so that Microchip can maintain continuity of supply and not disrupt customer orders.

Time Table Summary:

| | November 2022 | | | | > | | Janu | ary 2 | 2023 | | |
|----------------------------------|---------------|---|---|---|---|--|------|-------|------|---|---|
| Markuook | 4 | 4 | 4 | 4 | 4 | | 1 | 2 | 3 | 4 | 5 |
| workweek | | 6 | 7 | 8 | 9 | | | | | | |
| Qual Report Availability | | | | | | | | | | | Х |
| Final PCN Issue Date | | | Х | | | | | | | | |
| Estimated Implementation Date | | | | х | | | | | | | |

Method to Identify Change: Traceability Code

Partial Qualification Report:Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Note 1: The attached qualification report is incomplete but based on the available data and historical data, Microchip is confident that the pending qualification requirement will pass. The estimated qualification completion date will be on January 31, 2023. This final PCN will be updated to include the completed qualification report.

Note 2: Please be advised the qualification completion times may be extended because of unforeseen business conditions.

Revision History: November 17, 2022: Issued final notification.

The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable products.

Attachments:

PCN_ALAN-24AINW535_Pre and Post Change_Summary.pdf PCN_ALAN-24AINW535_Qual Report.pdf

Please contact your local Microchip sales office with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to <u>receive Microchip PCNs via email</u> please register for our PCN email service at our PCN home page select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the PCN FAQ section.

If you wish to <u>change your PCN profile, including opt out</u>, please go to the <u>PCN home page</u> select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.



QUALIFICATION REPORT SUMMARY RELIABILITY LABORATORY

PCN# ALAN-24AINW535

Date: December 10, 2010

Qualification of SST25VF032B-66-4C-S2AE catalog part number (CPN) available in 8L SOIJ (.208 in) package at MTAI assembly site. The qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers (CPN) available in 8L SOIJ (.208in) package will qualify by similarity (QBS)



| Purpose | Qualification of SST25VF032B-66-4C-S2AE catalog part number (CPN) available in 8L SOIJ (.208 in) package at MTAI assembly site. The qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers (CPN) available in 8L SOIJ (.208in) package will qualify by similarity (QBS). |
|---------------------|---|
| CN | BC102473 |
| QUAL ID | Q10094 Rev B |
| MP CODE | SST25VF032B |
| Part No. | SST25VF032B-66-4C-S2AE |
| Bonding No. | BDE-001251 Rev. 2.0 |
| CCB#: | 1012 and 5336 |
| Package | |
| Туре | 8L SOIJ |
| Package size | 208 mils |
| Lead Frame | |
| Paddle size | 140 x 160 mils |
| Material | CDA194 |
| Surface | Ag spot |
| Process | Stamped |
| Lead Lock | No |
| Part Number | 10100816 |
| Die attach material | |
| Ероху | 8390A |
| Wire | Au wire |
| Mold Compound | G600V |
| Plating Composition | Matte Tin |



Manufacturing Information

| Assembly Lot No. | Wafer Lot No. |
|------------------|---------------|
| A034602 | PN50400.00.B |
| A034603 | PN50400.00.B |
| A034604 | PN50400.00.B |

Result [X] Pass Fail

BL SOIJ (.208") assembled by MTAI pass reliability test per SSTQualification plan. This package was qualified the Moisture/Reflow Sensitivity Classification Level 1 at 260°C reflow temperature per IPC/JEDEC J-STD-020D standard.

PACKAGE QUALIFICATION REPORT Test Number Test Condition Microchip Qty. Date in Date Out Def/SS. Result Remarks (Reference) Spec (Acc.) MSL MSL Level 1/260°C 85°C/85%RH Moisture Soak 168 hrs. S12/14/16 10/05/10 0/66 Pass 66 09/23/10 System: TABAI ESPEC Model PR-3SPH (PDC) 3x Convection-Reflow 265°C max System: Vitronics Soltec MR1243

(IPC/JEDEC J-STD-020D)

| Drecondition | | | | | | | | |
|-------------------|---|--------------------|---------|----------|----------|--------|------|--------------|
| Electrical Test | Electrical Test :+25°C System: PK2 | S12/14/16 (PDC) | 1200(0) | 09/22/10 | 09/22/10 | 1200 | | Good Devices |
| Temp Cycle | Stress Condition: -65°C to +150°C, 5 Cycles System - TABALESPEC TSA-70H | PI-91020B | | 09/23/10 | 09/23/10 | 1200 | | |
| Bake | Bake 150°C, 24 hrs System: CHINEE | PI-92014B | | 09/23/10 | 09/24/10 | 1200 | | |
| Moisture Soak | 85°C/85%RH Moisture Soak 168 hrs. System: TABAI ESPEC Model PR-3SPH | PI-91173B | | 09/25/10 | 10/02/10 | 1200 | | |
| Convection-Reflow | 3x Convection-Reflow 265°C max | PI-91160B | | 10/02/10 | 10/02/10 | 1200 | | |
| | System: Vitronics Soltec MR1243 | | | | | | | |
| Electrical Test | Electrical Test :+25°C System: PK2 | S12/14/16 (PDC) | | 10/02/10 | 10/05/10 | 0/1200 | Pass | |

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | | Qty. (Acc.) | Date in | Date Out | Def/SS. | Result | Remarks |
|----------------------------|---|-----------|----------------|----------|----------|-------------|--------|-----------------------------------|
| | Stress Condition: -65°C to +150°C, 500 Cycles System : TABAI ESPEC TSA-70H Inspection: External crack inspection all units | PI-91020B | 30(0) | 10/07/10 | 10/19/10 | 240 0/30 | | Parts had been pre-conditioned |
| | | | 0.40(0) | 10/10/10 | 10/04/40 | 0/040 | Dees | |
| | Electrical lest: +25°C | 512/14/16 | 240(0) | 10/19/10 | 10/21/10 | 0/240 | Pass | |
| | System: PK2 | (PDC) | | | | | | |
| Temp Cycle | Stress Condition: -65°C to +150°C, 1000 Cycles System : TABAI ESPEC TSA-70H | PI-91020B | | 10/21/10 | 11/02/10 | 240 | | 80 units / lot |
| | Inspection: External crack inspection all units under 40X Optical magnification | QCI-33003 | 30(0) | 11/02/10 | 11/02/10 | 0/30 | | |
| | Electrical Test: +25°C | S12/14/16 | 240(0) | 11/02/10 | 11/03/10 | 0/240 | Pass | |
| | System: PK2 | (PDC) | | | | | | |
| Pressure Cooker | Stress Condition: +121°C, 100% RH, 15 PSI, 168 hrs. System: HIRAYAMA TPC-422R | PI-92013B | | 10/07/10 | 10/18/10 | 240 | | Parts had been pre-conditioned |
| | Electrical Test: +25°C | S12/14/16 | 240(0) | 10/18/10 | 10/18/10 | 0/240 | Pass | 80 units / lot |
| | System: PK2 | (PDC) | | | | | | |

PACKAGE QUALIFICATION REPORT

| Test Number (Reference) | Test Condition | Microchip Spec | Qty. (Acc.) | Date in | Date Out | Def/SS. | Result | Remarks |
|----------------------------|---|--------------------|----------------|----------|----------|---------|--------|-----------------------------------|
| HAST | Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X | PI-92010B | | 10/09/10 | 10/14/10 | 240 | | Parts had been pre-conditioned |
| naor | Electrical Test: +25°C System: PK2 | S12/14/16 (PDC) | 240(0) | 10/14/10 | 10/16/10 | 0/240 | Pass | 80 units / lot |
| | Stress Condition: +130°C/85%RH, 96 hrs. System: HAST 6000X | PI-91261B | | 10/07/10 | 10/12/10 | 240 | | Parts had been pre-conditioned |
| | Electrical Test: +25°C System: PK2 | S12/14/16 (PDC) | 240(0) | 10/12/10 | 10/12/10 | 0/240 | Pass | 80 units / lot |
| Solderability | Steam Aging: Temp 93°C,8Hrs System: SAS-3000 | QCI-31003 | 45 (0) | 10/07/10 | 10/08/10 | 45 | | 15 units / lot |
| Temp 245°C | Solder Dipping: Solder Temp.245°C | | | 10/08/10 | 10/08/10 | 45 | | |
| | Solder material: Pb Free Sn 95.5Ag3.9 Cu0.6 System: ERSA RA 2200D Visual Inspection: External Visual Inspection | | | 10/08/10 | 10/08/10 | 0/45 | Pass | |

PACKAGE QUALIFICATION REPORT

| | | | | | - | | | |
|-------------------------------------|--|------------------------|-----------------|----------|----------|---------|--------|-----------------------------------|
| Test Number (Reference) | Test Condition | Microchip Spec | Qty. (Acc.) | Date in | Date Out | Def/SS. | Result | Remarks |
| | Stress Condition: Bake 150°C, 168 hrs System: CHINEE | PI-92014B S12/14/16 | | 10/07/10 | 10/15/10 | 240 | | Parts had been pre-conditioned |
| | Electrical Test: +25°C System: PK2 | (PDC) | 240(0) | 10/15/10 | 10/16/10 | 0/240 | Pass | |
| High Temperature Storage Life | Stress Condition: Bake 150°C, 500 hrs System: CHINEE | PI-92014B S12/14/16 | | 10/16/10 | 10/31/10 | 240 | | 80 units / 1 lot |
| | Electrical Test: +25°C System: PK2 | (PDC) | 240 (0) | 10/31/10 | 11/01/10 | 0/240 | Pass | |
| | Stress Condition: Bake 150°C, 1000 hrs System: CHINEE | PI-92014B S12/14/16 | | 10/01/10 | 11/24/10 | 240 | | |
| | Electrical Test: +25°C System: PK2 | (PDC) | 240 (0) | 11/24/10 | 11/24/10 | 0240 | Pass | |
| Bond Strength Data Assembly | Bond Shear (15.00 grams) | 001 01022 | 30 (0) bonds | - | - | 0/30 | Pass | |
| | Wire Pull (> 2.5 grams) | QCI-91022 | 30 (0) wires | - | - | 0/30 | Pass | |



QUALIFICATION PLAN SUMMARY RELIABILITY LABORATORY

PCN# ALAN-24AINW535

Date: October 24, 2022

Qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers available in 8L SOIJ (.208in) package. **Purpose**: Qualification of MTAI as a new assembly site for SST26VF016-80-5I-S2AE and SST26VF016-80-5I-S2AE-T catalog part numbers available in 8L SOIJ (.208in) package.

| | Assembly site | MTAI |
|------------|--|-------------------------|
| | BD Number | BD-001048-01 |
| | MP Code (MPC) | X02017C3XH80 |
| Misc. | | X0201TC3XH80 |
| | Part Number (CPN) | SST26VF016-80-5I-S2AE |
| | | SST26VF016-80-5I-S2AE-T |
| | MSL information | 1 |
| | Assembly Shipping Media (T/R, Tube/Tray) | Tube / T&R |
| | Base Quantity Multiple (BQM) | 90 / 2100 |
| | Reliability Site | MTAI |
| | CCB# | 5336 |
| | Paddle size | 140 x 160 mils |
| | Material | CDA194 |
| | DAP Surface Prep | Bare Cu |
| | Treatment | Roughened |
| | Process | Stamped |
| Leau-Frame | Lead-lock | No |
| | Part Number | 10100840 |
| | Lead Plating | Matte tin |
| | Strip Size | 4R x 28C |
| | Strip Density | X112 |
| Bond Wire | Material | Au |
| Die Attach | Part Number | 8390A |
| Die Attach | Conductive | Yes |
| MC | Part Number | G600V |
| | PKG Type | SOIJ |
| <u>PKG</u> | Pin/Ball Count | 8 |
| | PKG width/size | 208 mils |

| Test Name | Conditions | Sample Size | Min. Qty of Spares per Lot (should be properly marked) | Qty of Lots | Total Units | Fail Accept Qty | Est. Dur. Days | ATE Test Site | REL Test Site | Special Instructions |
|---|--|--|--|-------------|----------------|--------------------|-------------------|---------------------|---------------------|---|
| Wire Bond Pull - WBP | Mil. Std. 883-2011 | 5 | 0 | 1 | 5 | 0 | 5 | | | 30 bonds from a min. 5 devices. |
| | | | | | | | | ΜΤΑΙ | MTAI | |
| Wire Bond Shear - WBS | CDF-AEC-Q100-001 | 5 | 0 | 1 | 5 | 0 | 5 | | | 30 bonds from a min. 5 devices. |
| Physical | Measure per JESD22 B100 and B108 | 10 | 0 | 1 | 10 | 0 | 5 | MTAI | MTAI | |
| Dimensions | | 10 | Ŭ | | 10 | 0 | Ű | | | |
| | | | | | | | | MTAI | MTAI | |
| External Visual | Mil. Std. 883-2009/2010 | All devices prior to submission for qualification testing | 0 | 1 | ALL | 0 | 5 | MTAI | MTAI | |
| Preconditioning - Required for surface mount devices | JESD22-A113 +150°C Bake for 24 hours, moisture loading requirements per MSL level + 3X reflow at peak reflow temperature per Jedec- STD-020E for package type; Electrical test pre and post stress at +25°C and 85 C MSL- 1@260 C | 231 | 15 | 1 | 246 | 0 | 15 | MTAI | MTAI | Spares should be properly identified. 77 parts from each lot to be used for HAST, uHAST, Temp Cycle test. |
| HAST | JESD22-A110 +130°C/85% RH for 96 hours or 110°C/85%RH for 264 hours. Electrical test pre and post stress at +25°C and 85C. Max temp testing at 85C. | 77 | 5 | 1 | 82 | 0 | 10 | MTAI | MTAI | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |
| UHAST | JESD22-A118 +130°C/85% RH for 96 hrs. or +110°C/85% RH for 264 hrs. Electrical test pre and post stress at +25°C | 77 | 5 | 1 | 82 | 0 | 10 | MTAI | МТАІ | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |
| Temp Cycle | JESD22-A104 -65°C to +150°C for 500 cycles. Electrical test pre and post stress at 25C and 85C; 3-gram force WBP, on 5 devices from 1 lot, test following Temp Cycle stress. Max temp testing at 85C. | 77 | 5 | 1 | 82 | 0 | 15 | MTAI | MTAI | Spares should be properly identified. Use the parts which have gone through Pre-conditioning. |

CCB 5336 Pre and Post Change Summary PCN# ALAN-24AINW535



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Pre and Post Change Summary





*Not fit to scale

ALAN-24AINW535 - CCB 5336 Final Notice: Qualification of MTAI as a new assembly site for SST26VF016-8C

Affected Catalog Part Numbers(CPN)

SST26VF016-80-5I-S2AE SST26VF016-80-5I-S2AE-T